

## Claim Amendments

Please amend the claims as follows:

1. (original) A method of conducting a circuit continuity test on an analog device having a first and a second node, said first and second node being coupled to a test circuit having a plurality of inputs, comprising the steps of:

providing a first voltage via a first resistor to said first node using a first input of said test circuit; and

measuring a second voltage at the first node via a second input of said test circuit,

wherein said measured second voltage is indicative of the internal circuit continuity of said analog device.

2. (original) The method of claim 1 wherein said measured second voltage is a diode drop below ground when the analog device first node has continuity.

3. (original) The method of claim 2 wherein the measured second voltage is the applied said first voltage when said analog device first node does not have continuity.

4. (original) The method of Claim 1 wherein said second voltage is measured at said first node without using a relay.

5. (original) The method of Claim 1 wherein said second voltage is measured via a second resistor being in parallel with said first resistor.

6. (original) The method of Claim 1 wherein said first voltage is negative voltage.

7. (original) The method of Claim 2 further comprising the step of simultaneously applying a third voltage to said second input node via a third resistor, and measuring a fourth voltage at said second node.

8. (original) The method of Claim 1 wherein said analog device is an operational amplifier.

9. (currently amended) A device, comprising:

an analog device having a first and second input node and including an internal diode coupled to said first node, said internal diode coupling said first node directly to ground;

a first external circuit coupled to said first node, said first circuit providing a first voltage via a first resistor; and

a second external circuit coupled to said first node without using a relay, said second circuit sensing a second voltage thereat via a second resistor, said second voltage and the corresponding operational state of said diode being indicative of the internal continuity of said analog device first node.

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10. (original) The device as recited in Claim 9, wherein said second circuit is coupled to and isolated from said first node via a second resistor.

11. (currently amended) The device as recited in Claim 9 wherein ~~said analog device includes a diode protection circuit having a diode coupled to said first node~~ wherein said second voltage produced at said first node is indicative of the voltage drop of said diode when the first node has continuity.

12. (original) The device as recited in Claim 9 wherein second circuit comprises a testing device, wherein said testing device is capable of measuring said second voltage produced at said first node.

13. (original) The device as recited in Claim 9 wherein said first voltage is a negative voltage.

14. (original) The device as recited in Claim 9 wherein said analog device is a differential amplifier.

15. (original) The device as recited in Claim 10 wherein said first and second resistors have the same value.

16. (original) In combination

an analog device having a first and second input terminal comprising a first and second node and a pair of output terminals;

a first resistor coupled to said first node, and first resistor receiving a first input voltage;

a second resistor coupled to said first node;

a third resistor coupled to the said second node, said third resistor receiving a second input voltage;

a fourth resistor coupled to said second node; and

wherein said second resistor and said fourth resistor communicate a voltage at said first node and said second node, respectively, that is indicative of the internal circuit continuity of said analog device.

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17. (original) The device as recited in Claim 16 wherein said analog device includes an internal diode coupled to said first node, and said voltage output across said second resistor is used to determine a voltage drop across said diode.

18. (original) The device as recited in Claim 16 wherein said first input voltage comprises a negative voltage.

19. (original) The device as recited in Claim 16 wherein said analog device is configured as a differential amplifier.

20. (original) The device as recited in Claim 17 wherein said second resistor and said fourth resistor are coupled to a testing device, wherein said testing device measures the voltage drop across said diode.

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21. (original) The device as recited in Claim 16 wherein said analog device has a pair of feedback circuits each providing feedback, one said feedback circuit being coupled between each said output terminal and one said respective input terminal.

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